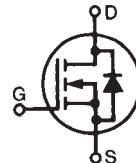


PolarHT™ Power MOSFET

IXTK 102N30P

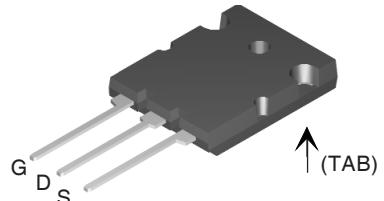
V_{DSS} = 300 V
 I_{D25} = 102 A
 $R_{DS(on)}$ = 33 mΩ

N-Channel Enhancement Mode



Symbol	Test Conditions	Maximum Ratings		
V_{DSS}	$T_J = 25^\circ\text{C}$ to 150°C	300		V
V_{DGR}	$T_J = 25^\circ\text{C}$ to 150°C ; $R_{GS} = 1 \text{ M}\Omega$	300		V
V_{GSM}		±20		V
I_{D25}	$T_c = 25^\circ\text{C}$	102		A
$I_{D(RMS)}$	External lead current limit	75		A
I_{DM}	$T_c = 25^\circ\text{C}$, pulse width limited by T_{JM}	250		A
I_{AR}	$T_c = 25^\circ\text{C}$	60		A
E_{AR}	$T_c = 25^\circ\text{C}$	60		mJ
E_{AS}	$T_c = 25^\circ\text{C}$	2.5		J
dv/dt	$I_s \leq I_{DM}$, $di/dt \leq 100 \text{ A}/\mu\text{s}$, $V_{DD} \leq V_{DSS}$, $T_J \leq 150^\circ\text{C}$, $R_G = 4 \Omega$	10		V/ns
P_D	$T_c = 25^\circ\text{C}$	700		W
T_J		-55 ... +150		°C
T_{JM}		150		°C
T_{stg}		-55 ... +150		°C
T_L	1.6 mm (0.062 in.) from case for 10 s	300		°C
M_d	Mounting torque	1.13/10	Nm/lb.in.	
Weight	TO-247	10		g

TO-264(SP) (IXTK)



G = Gate D = Drain
 S = Source TAB = Drain

Features

- International standard packages
- Unclamped Inductive Switching (UIS) rated
- Low package inductance
 - easy to drive and to protect

Advantages

- Easy to mount
- Space savings
- High power density

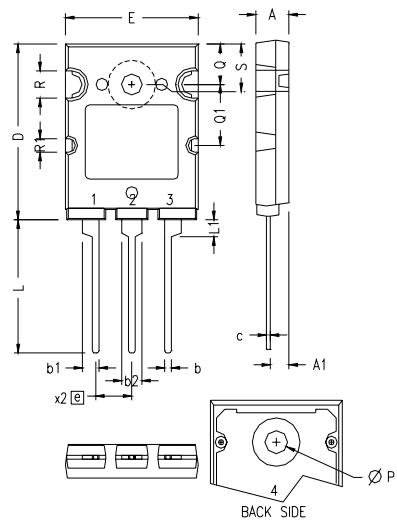
Symbol	Test Conditions ($T_J = 25^\circ\text{C}$, unless otherwise specified)	Characteristic Values		
		Min.	Typ.	Max.
V_{DSS}	$V_{GS} = 0 \text{ V}$, $I_D = 250 \mu\text{A}$	300		V
$V_{GS(th)}$	$V_{DS} = V_{GS}$, $I_D = 500 \mu\text{A}$	2.5		5.0 V
I_{GSS}	$V_{GS} = \pm 20 \text{ V}_{DC}$, $V_{DS} = 0$		±200	nA
I_{DSS}	$V_{DS} = V_{DSS}$ $V_{GS} = 0 \text{ V}$	$T_J = 125^\circ\text{C}$	25	μA
			250	μA
$R_{DS(on)}$	$V_{GS} = 10 \text{ V}$, $I_D = 0.5 I_{D25}$ Pulse test, $t \leq 300 \mu\text{s}$, duty cycle $d \leq 2 \%$		33	mΩ

PolarHT™ DMOS transistors
utilize proprietary designs and
process. US patent is pending.

Symbol	Test Conditions	Characteristic Values			
		(T _J = 25°C, unless otherwise specified)	Min.	Typ.	Max.
g_{fs}	V _{DS} = 10 V; I _D = 0.5 I _{D25} , pulse test	45	57	S	
C_{iss} C_{oss} C_{rss}	V _{GS} = 0 V, V _{DS} = 25 V, f = 1 MHz	7500		pF	
		1150		pF	
		230		pF	
t_{d(on)} t_r t_{d(off)} t_f	V _{GS} = 10 V, V _{DS} = 0.5 V _{DSS} , I _D = 60 A R _G = 3.3 Ω (External)	30		ns	
		28		ns	
		130		ns	
		30		ns	
Q_{g(on)} Q_{gs} Q_{gd}	V _{GS} = 10 V, V _{DS} = 0.5 V _{DSS} , I _D = 0.5 I _{D25}	224		nC	
		50		nC	
		110		nC	
R_{thJC}			0.18	K/W	
R_{thCK}		0.15		K/W	

Source-Drain Diode**Characteristic Values**(T_J = 25°C, unless otherwise specified)

Symbol	Test Conditions	Min.	typ.	Max.
I_s	V _{GS} = 0 V		102	A
I_{SM}	Repetitive		250	A
V_{SD}	I _F = I _S , V _{GS} = 0 V, Pulse test, t ≤ 300 μs, duty cycle d ≤ 2 %		1.5	V
t_{rr} Q_{RM}	I _F = 25 A -di/dt = 100 A/μs V _R = 100 V	250		ns
		3.3		μC

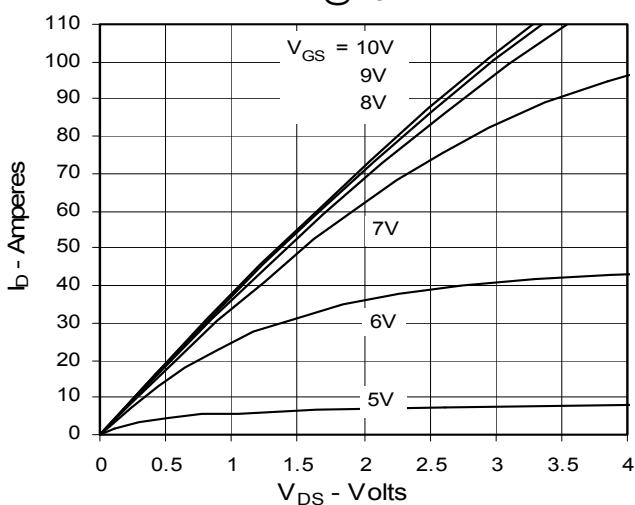
TO-264(SP) Outline (IXTK)

SYM	INCHES		MILLIMETERS	
	MIN	MAX	MIN	MAX
A	.185	.209	4.70	5.30
A1	.102	.118	2.60	3.00
b	.035	.049	0.90	1.25
b1	.091	.106	2.30	2.70
b2	.110	.126	2.80	3.20
c	.020	.033	0.50	0.85
D	1.012	1.035	25.70	26.30
E	.776	.799	19.70	20.30
e	.215BSC		5.46	BSC
L	.768	.807	19.50	20.50
L1	.091	.106	2.30	2.70
ØP	.122	.138	3.10	3.50
Q	.228	.244	5.80	6.20
Q1	.346	.362	8.80	9.20
ØR	.150	.165	3.80	4.20
ØR1	.071	.087	1.80	2.20
S	.228	.244	5.80	6.20

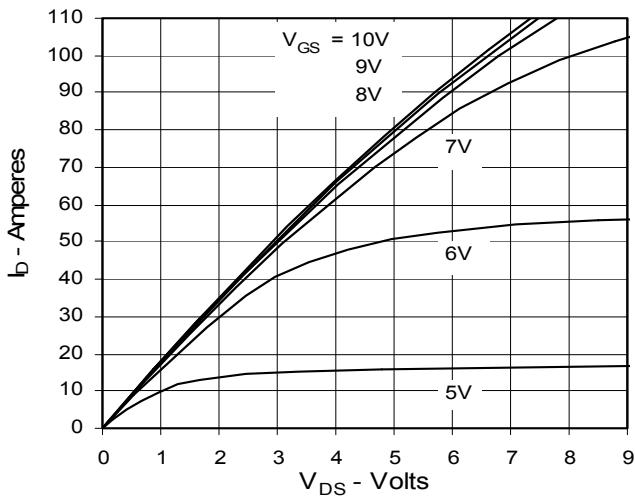
1 - GATE
2, 4 - DRAIN (COLLECTOR)
3 - SOURCE (EMITTER)

NOTE: Leads and back heatsink are solder plated.

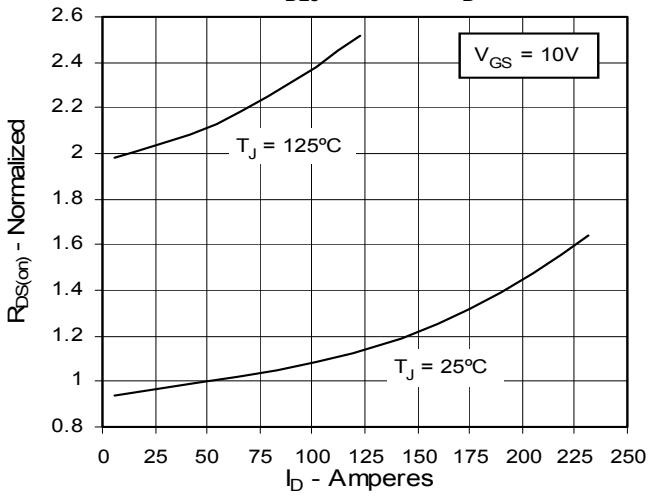
**Fig. 1. Output Characteristics
@ 25°C**



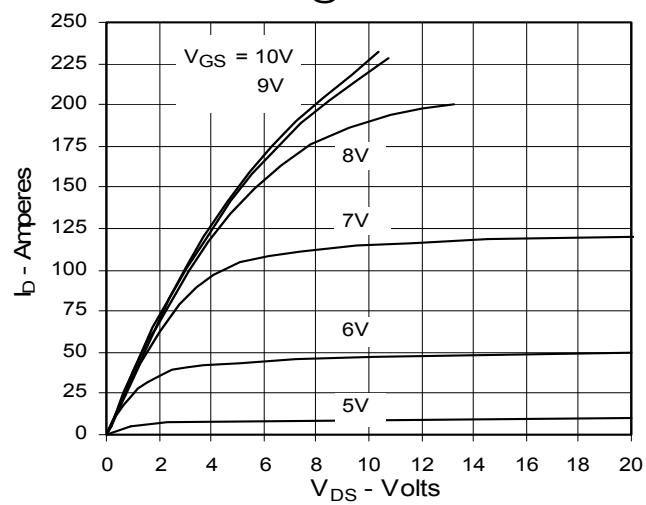
**Fig. 3. Output Characteristics
@ 125°C**



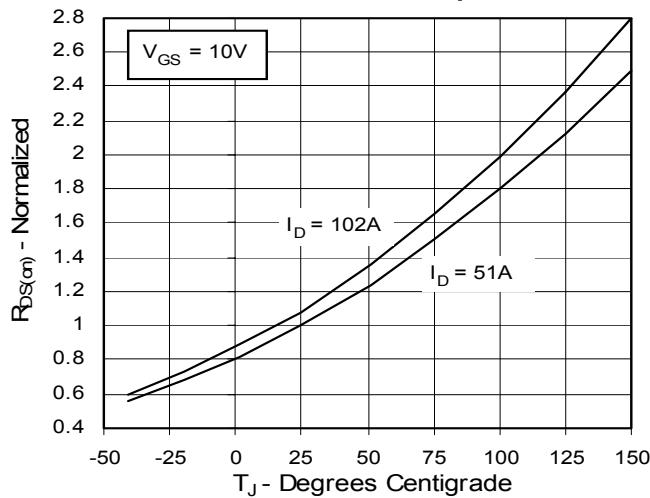
**Fig. 5. $R_{DS(on)}$ Normalized to
0.5 I_{D25} Value vs. I_D**



**Fig. 2. Extended Output Characteristics
@ 25°C**



**Fig. 4. $R_{DS(on)}$ Normalized to 0.5 I_{D25}
Value vs. Junction Temperature**



**Fig. 6. Drain Current vs. Case
Temperature**

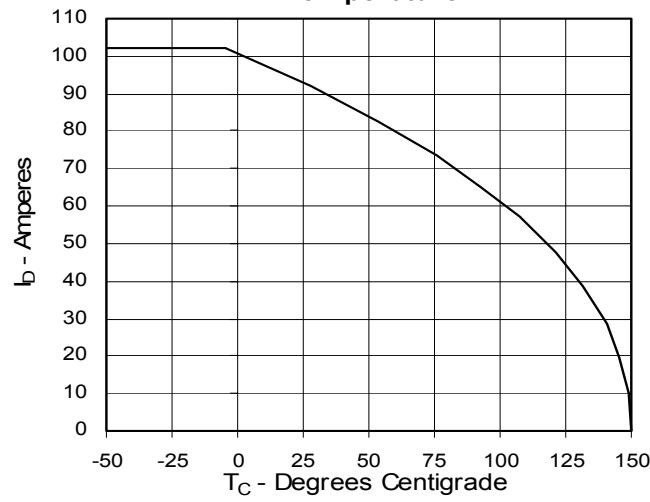


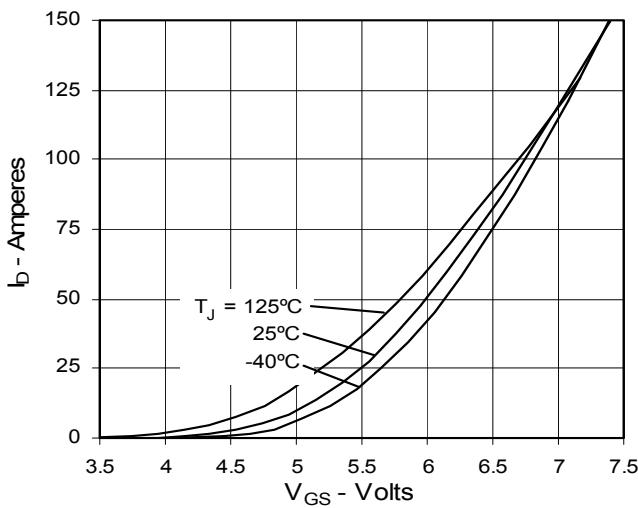
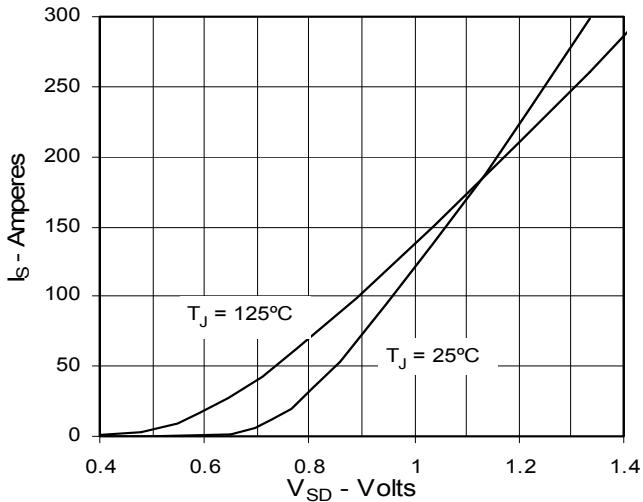
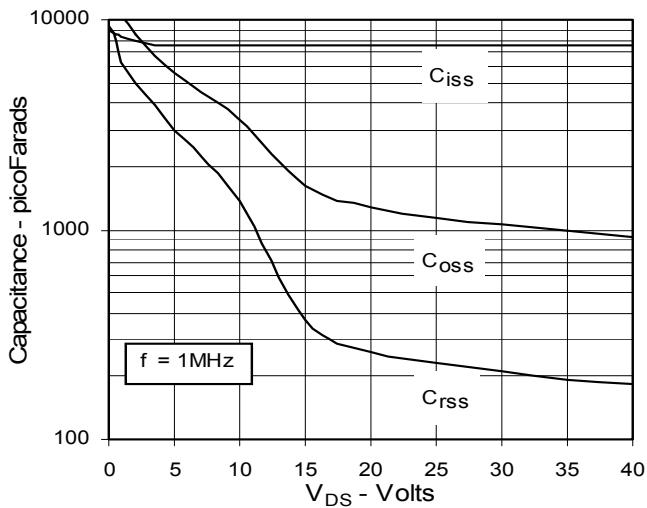
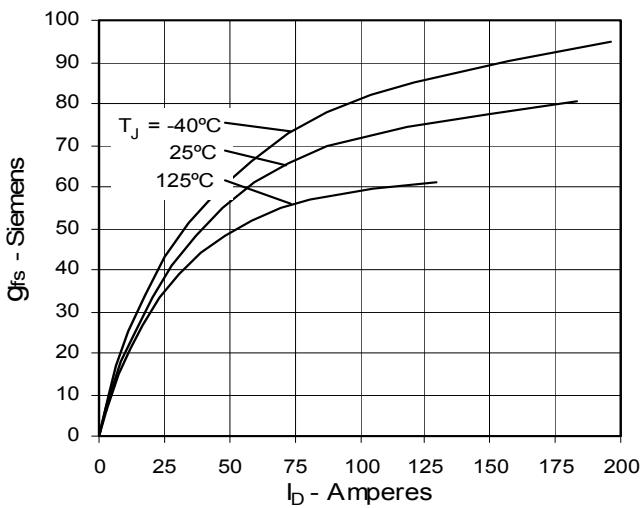
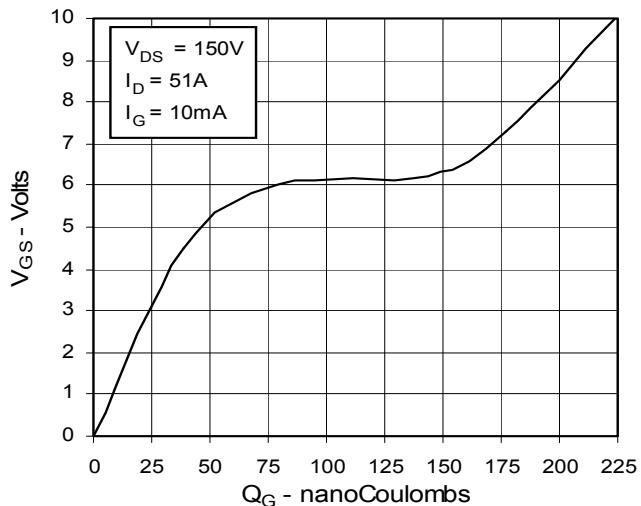
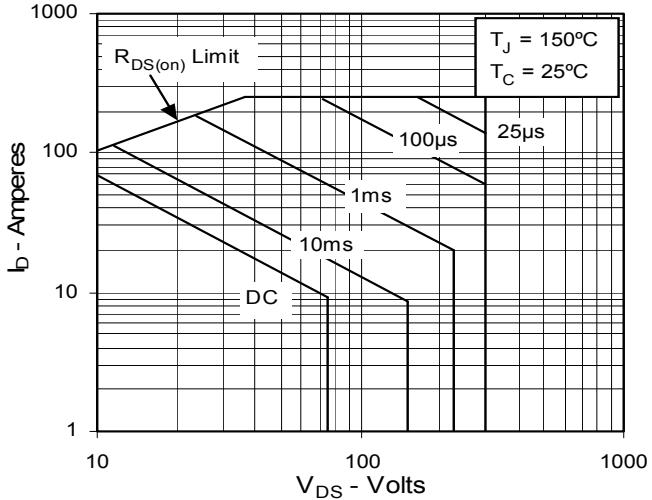
Fig. 7. Input Admittance

Fig. 9. Source Current vs. Source-To-Drain Voltage

Fig. 11. Capacitance

Fig. 8. Transconductance

Fig. 10. Gate Charge

Fig. 12. Forward-Bias Safe Operating Area


Fig. 13. Maximum Transient Thermal Resistance